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TERMINAL	DRAWINGS		CLAIMS ALLOWED		
	Sheets Drwg. Figs. Drwg.	Print Fig.	Total Claims	Print Claim for O.G	
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subsequent to (date)	(Assistant Examiner)	(Date)			
The term of this patent shall not extend beyond the expiration date	DONLE		ISSUE FEE		
of U.S Patent. No.	PRIMARY EXAMINER	5/2/2	Amount Due	Date Paid	
The terminalmonths of this patent have been disclaimed.	(Primary Examiner)	(Oyte)	100110000	TOU NUMBER	
FINAL SPRE REVIEW			ISSUE BA	TCH NUMBER	
(INITIALS)	(Legal Instruments Examiner)	(Date)			

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